

AMENDMENTS TO THE CLAIMS

This listing of claims will replace all prior versions and listings of claims in the application:

Claim 1: (Cancelled)

2. (New) A method of quantifying faults in an integrated circuit device under test, the method comprising:

testing a plurality of individual circuit cells that have been determined to be normal to generate normal voltage contrast characteristics for each of the circuit cells;

creating a reference library that includes the generated normal voltage contrast characteristics for each of the tested circuit cells;

sequentially determining if circuit cells included in the integrated circuit device under test are included in the reference library;

in the event that a circuit cell included in the integrated circuit device under test is included in the reference library, comparing the voltage contrast characteristics of said circuit cell with the corresponding normal voltage contrast characteristics include in the reference library; and

in the vent that said circuit cell is not included in the reference library, determining normal voltage contrast characteristics for said cell and including said normal voltage contrast characteristics in the reference library.